



12500 TI Boulevard, MS 8640, Dallas, Texas 75243

Revision A is to update the ZVEI ID and Changes to the Product Identification section of the shipping/2D label to reflect the correct Moisture Sensitivity Level (MSL) classification.

Notification Number:	20260803001.0A	Notification Issued	September 04, 2026
MSL Update for Select Device			

Change Type(s)	Packing/Shipping/Labeling
ZVEI ID	SEM-PS-02

Notification Details

Description of Change:								
This Notification is to inform of a change to the MSL ratings for the device listed below as follows:								
Group 1 device:	<table><tr><th></th><th>Current</th><th>New</th></tr><tr><td>MSL level</td><td>3</td><td>1</td></tr></table>			Current	New	MSL level	3	1
	Current	New						
MSL level	3	1						
Group 2 device:	<table><tr><th></th><th>Current</th><th>New</th></tr><tr><td>MSL level</td><td>2</td><td>1</td></tr></table>			Current	New	MSL level	2	1
	Current	New						
MSL level	2	1						
Reason for Change:	Supply Continuity							

Anticipated impact on Form, Fit, Function, Quality or Reliability:	None
Changes to product identification resulting from this PCN:	Sample product shipping label (not actual product label): 

Group 1 Products Affected:		
MLA00058DRG4	ULQ2003ATDRRBG4	TLV2434AQPWRQ1
Group 2 Products Affected:		
M0C1103QDDFRQ1	M0C1104QDDFRQ1	
M0C1103QDYRQ1	M0C1104QDYRQ1	

Group 1 Qualification Report

Automotive New Product Qualification Summary (As per AEC-Q100 Rev. H and JEDEC Guidelines)

ULQ2003AQDRQ1 MLA

Approve Date 10-MARCH-2025

Product Attributes

Attributes	Qual Device: <u>ULQ2003AQDRQ1</u>	QBS Process Reference: <u>MC33063AQDRQ1</u>	QBS Package Reference: <u>OPA2991QDRQ1</u>	QBS Product Reference: <u>ULQ2003AQDRQ1</u>
Automotive Grade Level	Grade 1	Grade 1	Grade 1	Grade 1
Operating Temp Range (C)	-40 to 125	-40 to 125	-40 to 125	-40 to 125
Product Function	Power Management	Power Management	Signal Chain	Power Management
Wafer Fab Supplier	RFAB	RFAB	RFAB	RFAB
Assembly Site	MLA	FMX	MLA	FMX
Package Group	SOIC	SOIC	SOIC	SOIC
Package Designator	D	D	D	D
Pin Count	16	8	8	16

QBS: Qual By Similarity

Qual Device ULQ2003AQDRQ1 is qualified at MSL1 260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device: <u>ULQ2003AQDRQ1</u>	QBS Process Reference: <u>MC33063AQDRQ1</u>	QBS Package Reference: <u>OPA2991QDRQ1</u>	QBS Product Reference: <u>ULQ2003AQDRQ1</u>
Test Group A - Accelerated Environment Stress Tests											
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL1 260C	-	No Fails	-	No Fails	-
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST	130C/85%RH	96 Hours	1/77/0	-	3/231/0	-
AC/UHAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Autoclave	121C/15psig	96 Hours	1/77/0	-	-	-
AC/UHAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Unbiased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-
TC	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-65C/150C	500 Cycles	3/231/0	-	3/231/0	-
TC-BP	A4	MIL-STD883 Method 2011	1	5	Post Temp Cycle Bond Pull	-	-	1/5/0	-	1/5/0	-
PTC	A5	JEDEC JESD22-A105	1	45	PTC	-40/125C	1000 Cycles	1/45/0	-	-	-
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	150C	1000 Hours	3/135/0	-	3/135/0	-
Test Group B - Accelerated Lifetime Simulation Tests											
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	125C	1000 Hours	-	3/231/0	-	-

HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	150C	300 Hours	-	-	-	3/231/0
ELFR	B2	AEC Q100-008	3	800	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-	-
Test Group C - Package Assembly Integrity Tests											
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	3/90/0	-	3/90/0	-
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	3/90/0	-	3/90/0	-
SD	C3	JEDEC J-STD-002	1	15	PB Solderability	>95% Lead Coverage	-	1/15/0	-	-	-
SD	C3	JEDEC J-STD-002	1	15	PB-Free Solderability	>95% Lead Coverage	-	1/15/0	-	-	-
PD	C4	JEDEC JESD22-B100 and B108	3	10	Physical Dimensions	Cpk>1.67	-	3/30/0	-	3/30/0	-
Test Group D - Die Fabrication Reliability Tests											
EM	D1	JESD61	-	-	Electromigration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
Tddb	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
HCI	D3	JESD60 & 28	-	-	Hot Carrier Injection	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
BTI	D4	-	-	-	Bias Temperature Instability	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
Test Group E - Electrical Verification Tests											
ESD	E2	AEC Q100-002	1	3	ESD HBM	-	2000 Volts	-	1/3/0	1/3/0	1/3/0
ESD	E3	AEC Q100-011	1	3	ESD CDM	-	750 Volts	1/3/0	1/3/0	1/3/0	1/3/0
LU	E4	AEC Q100-004	1	6	Latch-Up	Per AEC Q100-004	-	-	1/6/0	1/6/0	1/6/0
ED	E5	AEC Q100-009	3	30	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	1/30/0	3/90/0	3/90/0	3/90/0

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40C to +150C

Grade 1 (or Q): -40C to +125C

Grade 2 (or T): -40C to +105C

Grade 3 (or I) : -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED

Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room : AC/uHAST

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-CHG-2205-003

Automotive Qualification Summary

(As per AEC and JEDEC Guidelines)

Q006 SOIC at MLA
Approve Date 19-MAY -2022

Attributes	Qual Device: <u>OPA2991QDRQ1</u>
Automotive Grade Level	Grade 1
Operating Temp Range (C)	-40 to 125
Product Function	Signal Chain
Wafer Fab Supplier	RFAB
Assembly Site	MLA
Package Group	SOIC
Package Designator	D
Pin Count	8

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device: <u>OPA2991QDRQ1</u>
Test Group A - Accelerated Environment Stress Tests								
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL1 260C	-	3/924/0
PC	A1.1	-	3	22	SAM Precon Pre	Review for delamination	-	3/66/0
PC	A1.2	-	3	22	SAM Precon Post	Review for delamination	-	3/66/0
HAST	A2.1	JEDEC JESD22-A110	3	77	Biased HAST	130C/85%RH	96 Hours	3/231/0
HAST	A2.1.2	-	3	1	Cross Section, post bHAST, 1X	Post stress cross section	Completed	3/3/0
HAST	A2.1.3	-	3	3	Wire Bond Shear, post bHAST, 1X	Post stress	-	3/9/0
HAST	A2.1.4	-	3	3	Bond Pull over Stitch, post bHAST, 1X	Post stress	-	3/9/0
HAST	A2.1.5	-	3	3	Bond Pull over Ball, post bHAST, 1X	Post stress	-	3/9/0
HAST	A2.2	JEDEC JESD22-A110	3	70	Biased HAST	130C/85%RH	192 Hours	3/231/0
HAST	A2.2.1	-	3	22	SAM Analysis, post bHAST 2X	Review for delamination	Completed	3/66/0
HAST	A2.2.2	-	3	1	Cross Section, post bHAST, 2X	Post stress cross section	Completed	3/3/0
HAST	A2.2.3	-	3	3	Wire Bond Shear, post bHAST, 2X	Post stress	-	3/9/0
HAST	A2.2.4	-	3	3	Bond Pull over Stitch, post bHAST, 2X	Post stress	-	3/9/0
HAST	A2.2.5	-	3	3	Bond Pull over Ball, post bHAST, 2X	Post stress	-	3/9/0
TC	A4.1	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-65C/150C	500 Cycles	3/231/0
TC	A4.1.1	-	3	22	SAM Analysis, post TC 1X	Review for delamination	Completed	3/66/0
TC	A4.1.2	-	3	1	Cross Section, post TC, 1X	Post stress cross section	Completed	3/3/0

TC	A4.1.3	-	3	3	Wire Bond Shear, post TC, 1X	Post stress	-	3/9/0
TC	A4.1.4	-	3	3	Bond Pull over Stitch, post TC, 1X	Post stress	-	3/9/0
TC	A4.1.5	-	3	3	Bond Pull over Ball, post TC, 1X	Post stress	-	3/9/0
TC	A4.2	JEDEC JESD22-A104 and Appendix 3	3	70	Temperature Cycle	-65C/150C	1000 Cycles	3/231/0
TC	A4.2.1	-	3	22	SAM Analysis, post TC, 2X	Review for delamination	Completed	3/66/0
TC	A4.2.2	-	3	1	Cross Section, post TC, 2X	Post stress cross section	Completed	3/3/0
TC	A4.2.3	-	3	3	Wire Bond Shear, post TC, 2X	Post stress	-	3/9/0
TC	A4.2.4	-	3	3	Bond Pull over Stitch, post TC, 2X	Post stress	-	3/9/0
TC	A4.2.5	-	3	3	Bond Pull over Ball, post TC, 2X	Post stress	-	3/9/0
HTSL	A6.1	JEDEC JESD22-A103	3	45	High Temperature Storage Life	150C	1000 Hours	3/135/0
HTSL	A6.1.1	-	3	1	Cross Section, post HTSL, 1X	Post stress cross section	Completed	3/3/0
HTSL	A6.2	JEDEC JESD22-A103	3	44	High Temperature Storage Life	150C	2000 Hours	3/135/0
HTSL	A6.2.1	-	3	1	Cross Section, post HTSL, 2X	Post stress cross section	Completed	3/3/0
Test Group C - Package Assembly Integrity Tests								
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	3/90/0
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	3/90/0

QBS: Qual By Similarity, also known as Generic Data

Qual Device OPA2991QDRQ1 is qualified at MSL1 260C

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40C to +150C

Grade 1 (or Q): -40C to +125C

Grade 2 (or T): -40C to +105C

Grade 3 (or I) : -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED

Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room : AC/uHAST

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-BKF-2205-008

Automotive New Product Qualification Summary (As per AEC-Q100 Rev. H and JEDEC Guidelines)

Approve Date 27-February-2024

Product Attributes

Attributes	Qual Device:	QBS Process Reference:	QBS Package Reference:	QBS Package, Process, Product Reference:
	OPA4990QPWRQ1	OPA2991QDGKRO1	SN74HCS74QPWRQ1	OPA4991QPWRQ1
Automotive Grade Level	Grade 1	Grade 1	Grade 1	Grade 1
Operating Temp Range (C)	-40 to 125	-40 to 125	-40 to 125	-40 to 125
Product Function	Signal Chain	Signal Chain	Logic	Signal Chain
Wafer Fab Supplier	RFAB	RFAB	RFAB	RFAB
Assembly Site	MLA	HFTFAT	MLA	MLA
Package Group	TSSOP	VSSOP	TSSOP	TSSOP
Package Designator	PW	DGK	PW	PW
Pin Count	14	8	14	14

QBS: Qual By Similarity

Qual Device OPA4990QPWRQ1 is qualified at MSL1 260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device: OPA4990QPWRQ1	QBS Process Reference: OPA2991QDGKRO1	QBS Package Reference: SN74HCS74QPWRQ1	QBS Package, Process, Product Reference: OPA4991QPWRQ1
Test Group A - Accelerated Environment Stress Tests											
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL1 260C	-	1/Pass	3/Pass	3/Pass	1/Pass
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST	110C/85%RH	264 Hours	-	-	-	1/77/0
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST	130C/85%RH	96 Hours	1/77/0	3/231/2	3/231/0	-
AC/UHAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Autoclave	121C/15psig	96 Hours	-	3/231/0	3/231/0	3/231/0
AC/UHAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Unbiased HAST	130C/85%RH	96 Hours	1/77/0	-	-	-
TC	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	3/231/0	3/231/0	1/77/0
TC-BP	A4	MIL-STD883 Method 2011	1	5	Post Temp Cycle Bond Pull	-	-	1/5/0	-	-	1/5/0
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	1/45/0
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	175C	500 Hours	1/45/0	-	-	-
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	175C	630 Hours	-	3/135/0	-	-
Test Group B - Accelerated Lifetime Simulation Tests											

HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	125C	1000 Hours	-	-	3/231/0	-
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	150C	300 Hours	1/77/0	-	-	3/231/0
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	150C	408 Hours	-	3/231/1 ¹	-	-
ELFR	B2	AEC Q100-008	3	800	Early Life Failure Rate	125C	48 Hours	-	3/2400/4 ²	3/2400/0	-
Test Group C - Package Assembly Integrity Tests											
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	3/90/0	3/90/0	1/30/0
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	3/90/0	3/90/0	1/30/0
SD	C3	JEDEC J-STD-002	1	15	PB Solderability	>95% Lead Coverage	-	-	1/15/0	1/15/0	-
SD	C3	JEDEC J-STD-002	1	15	PB-Free Solderability	>95% Lead Coverage	-	-	1/15/0	1/15/0	-
PD	C4	JEDEC JESD22-B100 and B108	3	10	Physical Dimensions	Cpk>1.67	-	1/10/0	3/30/0	3/30/0	1/10/0
Test Group D - Die Fabrication Reliability Tests											
EM	D1	JESD61	-	-	Electromigration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
Tddb	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
HCI	D3	JESD60 & 28	-	-	Hot Carrier Injection	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
BTI	D4	-	-	-	Bias Temperature Instability	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
Test Group E - Electrical Verification Tests											
ESD	E2	AEC Q100-002	1	3	ESD HBM	-	2000 Volts	1/3/0	1/3/0	1/3/0	-
ESD	E2	AEC Q100-002	1	3	ESD HBM	-	4000 Volts	-	-	-	1/3/0
ESD	E3	AEC Q100-011	1	3	ESD CDM	-	1500 Volts	-	-	-	1/3/0
ESD	E3	AEC Q100-011	1	3	ESD CDM	-	500 Volts	1/3/0	-	1/3/0	-
LU	E4	AEC Q100-004	1	6	Latch-Up	Per AEC Q100-004	-	1/6/0	1/6/0	1/6/0	3/18/0
ED	E5	AEC Q100-009	3	30	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	3/90/0	3/90/0	3/90/0	3/90/0

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40C to +150C

Grade 1 (or Q): -40C to +125C

Grade 2 (or T): -40C to +105C

Grade 3 (or I) : -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED

Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room : AC/uHAST

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-NPD-2305-114

[1]-One unit failed due to bad BI socket contact
 [2]-Three units failed due to bad BI socket contact, and
 one due to reverse-insertion

Automotive Qualification Summary (As per AEC and JEDEC Guidelines)

Q006 TSSOP at MLA
 Approve Date 19-MAY -2022

Attributes	Qual Device: <u>OPA4990QPWRQ1</u>	QBS Process Reference: <u>OPA2991QDGKRQ1</u>	QBS Package Reference: <u>SN74HCS74QPWRQ1</u>	QBS Package, Process, Product Reference: <u>OPA4991QPWRQ1</u>
Automotive Grade Level	Grade 1	Grade 1	Grade 1	Grade 1
Operating Temp Range (C)	-40 to 125	-40 to 125	-40 to 125	-40 to 125
Product Function	Signal Chain	Signal Chain	Logic	Signal Chain
Wafer Fab Supplier	RFAB	RFAB	RFAB	RFAB
Assembly Site	MLA	HFTFAT	MLA	MLA
Package Group	TSSOP	VSSOP	TSSOP	TSSOP
Package Designator	PW	DGK	PW	PW
Pin Count	14	8	14	14

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device: <u>OPA4990QPWRQ1</u>	QBS Reference: <u>OPA2991QDGKRQ1</u>	QBS Reference: <u>SN74HCS74QPWRQ1</u>	QBS Reference: <u>OPA4991QPWRQ1</u>
Test Group A - Accelerated Environment Stress Tests											
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL1 260C	-	-	3/Pass	3/Pass	1/Pass
PC	A1.1	-	3	22	SAM Precon Pre	Review for delamination	-	-	3/66/0	3/66/0	1/22/0
PC	A1.2	-	3	22	SAM Precon Post	Review for delamination	-	-	3/66/0	3/66/0	1/22/0
HAST	A2.1	JEDEC JESD22-A110	3	77	Biased HAST	110C/85%RH	264 Hours	-	-	-	1/77/0
HAST	A2.1	JEDEC JESD22-A110	3	77	Biased HAST	130C/85%RH	96 Hours	-	3/231/2	3/231/0	-
HAST	A2.1.2	-	3	1	Cross Section, post bHAST, 1X	Post stress cross section	Completed	-	3/3/0	3/3/0	1/1/0
HAST	A2.1.3	-	3	3	Wire Bond Shear, post bHAST, 1X	Post stress	-	-	3/9/0	3/9/0	1/3/0
HAST	A2.1.4	-	3	3	Bond Pull over Stitch, post bHAST, 1X	Post stress	-	-	3/9/0	3/9/0	1/3/0
HAST	A2.1.5	-	3	3	Bond Pull over Ball, post bHAST, 1X	Post stress	-	-	3/9/0	3/9/0	1/3/0
HAST	A2.2	JEDEC JESD22-A110	3	70	Biased HAST	110C/85%RH	528 Hours	-	-	-	1/77/0
HAST	A2.2	JEDEC JESD22-A110	3	70	Biased HAST	130C/85%RH	192 Hours	-	3/231/0	3/231/0	-
HAST	A2.2.1	-	3	22	SAM Analysis, post bHAST 2X	Review for delamination	Completed	-	3/66/0	3/66/0	1/22/0
HAST	A2.2.2	-	3	1	Cross Section, post bHAST, 2X	Post stress cross section	Completed	-	3/3/0	3/3/0	1/1/0

HAST	A2.2.3	-	3	3	Wire Bond Shear, post bHAST, 2X	Post stress	-	-	3/9/0	3/9/0	1/3/0
HAST	A2.2.4	-	3	3	Bond Pull over Stitch, post bHAST, 2X	Post stress	-	-	3/9/0	3/9/0	1/3/0
HAST	A2.2.5	-	3	3	Bond Pull over Ball, post bHAST, 2X	Post stress	-	-	3/9/0	3/9/0	1/3/0
TC	A4.1	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	3/231/0	1/77/0
TC	A4.1.1	-	3	22	SAM Analysis, post TC, 1X	Review for delamination	Completed	-	3/66/0	3/66/0	1/22/0
TC	A4.1.2	-	3	1	Cross Section, post TC, 1X	Post stress cross section	Completed	-	3/3/0	3/3/0	1/1/0
TC	A4.1.3	-	3	3	Wire Bond Shear, post TC, 1X	Post stress	-	-	3/9/0	3/9/0	1/3/0
TC	A4.1.4	-	3	3	Bond Pull over Stitch, post TC, 1X	Post stress	-	-	3/9/0	3/9/0	1/3/0
TC	A4.1.5	-	3	3	Bond Pull over Ball, post TC, 1X	Post stress	-	-	3/9/0	3/9/0	1/3/0
TC	A4.2	JEDEC JESD22-A104 and Appendix 3	3	70	Temperature Cycle	-65C/150C	1000 Cycles	-	3/231/0	3/231/0	1/77/0
TC	A4.2.1	-	3	22	SAM Analysis, post TC, 2X	Review for delamination	Completed	-	3/66/0	3/66/0	1/22/0
TC	A4.2.2	-	3	1	Cross Section, post TC, 2X	Post stress cross section	Completed	-	3/3/0	3/3/0	1/1/0
TC	A4.2.3	-	3	3	Wire Bond Shear, post TC, 2X	Post stress	-	-	3/9/0	3/9/0	1/3/0
TC	A4.2.4	-	3	3	Bond Pull over Stitch, post TC, 2X	Post stress	-	-	3/9/0	3/9/0	1/3/0
TC	A4.2.5	-	3	3	Bond Pull over Ball, post TC, 2X	Post stress	-	-	3/9/0	3/9/0	1/3/0
HTSL	A6.1	JEDEC JESD22-A103	3	45	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	1/45/0
HTSL	A6.1	JEDEC JESD22-A103	3	45	High Temperature Storage Life	175C	630 Hours	-	3/135/0	-	-
HTSL	A6.1.1	-	3	1	Cross Section, post HTSL, 1X	Post stress cross section	Completed	-	3/3/0	3/3/0	1/1/0
HTSL	A6.2	JEDEC JESD22-A103	3	44	High Temperature Storage Life	150C	2000 Hours	-	-	3/135/0	1/45/0
HTSL	A6.2	JEDEC JESD22-A103	3	44	High Temperature Storage Life	175C	1000 Hours	-	3/135/0	-	-
HTSL	A6.2.1	-	3	1	Cross Section, post HTSL, 2X	Post stress cross section	Completed	-	3/3/0	3/3/0	1/1/0
Test Group C - Package Assembly Integrity Tests											
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	3/90/0	3/90/0	1/30/0
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull	Minimum of 5 devices, 30 wires Cpk>1.67	Wires	1/30/0	3/90/0	3/90/0	1/30/0

QBS: Qual By Similarity

Qual Device OPA4990QPWRQ1 is qualified at MSL1 260C

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Texas Instruments Incorporated TI Information - Selective Disclosure Notification PCN#20260803001.0

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40C to +150C
Grade 1 (or Q): -40C to +125C
Grade 2 (or T): -40C to +105C
Grade 3 (or I) : -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED
Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU
Room : AC/uHAST

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>
TI Qualification ID: R-NPD-2305-114

Group 2 Qualification Report

Automotive New Product Qualification Summary
(As per AEC-Q100 Rev. J and JEDEC Guidelines)

Qualification Report for MOL* Products in SOT Packages in LFAB
Approve Date 23-SEPTEMBER-2024

Product Attributes

Attributes	Qual Device: M0L1306QDYRQ1	QBS Reference: M0G3507QPMRQ1	QBS Reference: M0G3507QPMRQ1	QBS Reference: M0L306QRHBRQ1	QBS Reference: TMS320F2837X*PTPQ	QBS Reference: CC2642R1TWRGZRQ1	QBS Reference: M0L1306QDYRQ1
Automotive Grade Level	Grade 1	Grade 1	Grade 1	Grade 1	Grade 1	Grade 2	Grade 1
Operating Temp Range (C)	-40 to 125	-40 to 125	-40 to 125	-40 to 125	-40 to 125	-40 to 105	-40 to 125
Product Function	Microcontroller	Microcontroller	Microcontroller	Microcontroller	Microcontroller	Microcontroller	Microcontroller
Wafer Fab Supplier	LFAB	LFAB	UMCI	LFAB	UMCI, LFAB	LFAB	UMCI
Assembly Site	PHI	PHI	PHI	CDAT	PHI	CDAT / CLARK-AT	PHI
Package Group	SOT	QFP	QFP	QFN	QFP	QFN	SOT
Package Designator	DYY	PM	PM	RHB	PTP	RGZ	DYY
Pin Count	16	64	64	32	176	48	16

QBS: Qual By Similarity, also known as Generic Data
Qual Device XM0L1306QDYRQ1 is qualified at MSL1 260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device: M0L1306QDYRQ1	QBS PRODUCT Reference: M0G3507QPMRQ1	QBS PRODUCT Reference: M0G3507QPMRQ1	QBS PRODUCT Reference: M0L306QRHBRQ1	QBS PRODUCT Reference: TMS320F2837X*PTPQ	QBS PRODUCT Reference: CC2642R1TWRGZRQ1	QBS PRODUCT Reference: M0L1306QDYRQ1
Test Group A - Accelerated Environment Stress Tests														
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL2 260C	-	1/77/0 + QBS QBS M0L1306QDYRQ1 + Reference Devices	QBS M0G3507QPMRQ1+ TMS320F2837X*PTPQ	3/462/0 + QBS TMS320F2837X*PTPQ	-	6/1125/0 ¹	-	3/692/0 ³
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL1 260C	-	QBS M0L1306QDYRQ1 + Reference Devices	-	-	-	-	3/828/0 ²	3/231/0
HAST	A2	JEDEC JESD22-A110	3	77	Biased HAST	130C/85%RH	96 Hours	QBS M0L1306QDYRQ1 + Reference Devices	QBS TMS320F2837X*PTPQ	QBS TMS320F2837X*PTPQ	-	6/462/0	3/231/0	3/231/0

AC/UHAST	A3	JEDEC JESD22-A102/JEDEC JESD22-A118	3	77	Unbiased HAST	130C/85%RH	96 Hours	1/770 + QBS MOL1306QYRQ1 + Reference Devices	QBS TMS320F2837X*PTPQ	QBS TMS320F2837X*PTPQ	-	6/462/0	3/231/0	3/231/0
TC	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-65C/150C	500 Cycles	1/5/0	QBS TMS320F2837X*PTPQ	3/231/0	-	6/462/0	3/231/0 ²	3/231/0 ⁴
TC-BP	A4	MIL-STD883 Method 2011	1	5	Post Temp Cycle Bond Pull	-	-	QBS QBS MOL1306QYRQ1 + References Devices	QBS TMS320F2837X*PTPQ	1/5/0	-	2/10/0	1/5/0	1/5/0
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life	150C	1000 Hours	1/770 + QBS QBS MOL1306QYRQ1 + Reference Devices	QBS TMS320F2837X*PTPQ	QBS TMS320F2837X*PTPQ	-	6/270/0	3/135/0	3/135/0
Test Group B - Accelerated Lifetime Simulation Tests														
HTOL	B1	JEDEC JESD22-A108	3	77	Life Test	125C	1000 Hours	QBS MOG3507QPMRQ1 + Reference Devices	1/770 + QBS Reference Devices	3/231/0	3/231/0	6/462/0	6/462/0 ⁵	QBS MOG3507QPMRQ1 + Reference Devices
ELFR	B2	AEC Q100-008	3	800	Early Life Failure Rate	125C	48 Hours	QBS MOG3507QPMRQ1 + Reference Devices	1/800/0 + QBS TMS320F28379SPTPQ	2/1600/0	QBS TMS320F28379SPTPQ	6/4800/0	6/4800/0 ⁶	QBS TMS320F28379SPTPQ
EDR	B3	AEC Q100-105	3	77	Data Retention	150C	1000 Hours	QBS MOG3507QPMRQ1 + Reference Devices	1/770 + QBS Reference Devices	3/231/0	3/231/0	6/462/0	6/462/0	QBS MOG3507QPMRQ1 + Reference Devices
EDR	B3	AEC Q100-105	3	77	Endurance Cycling	-40C, 25C, 125C	≥10K cycles	QBS MOG3507QPMRQ1 + Reference Devices	3/231/0 (1/770 for each temperature)	3/231/0 (1/770 for each temperature)	3/231/0 (1/770 for each temperature)	6/462/0 (2/154/0 for each temperature)	6/462/0 ⁷	QBS MOG3507QPMRQ1 + Reference Devices
Test Group C - Package Assembly Integrity Tests														
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear	Minimum of 5 devices, 30 wires Cpk-1.67	Wires	3/90/0	3/90/0	3/90/0	3/90/0	3/90/0	1/30/0	6/180/0
WBP	C2	MIL-STD883 Method 2011	1	30	Wire Bond Pull	Minimum of 5 devices, 30 wires Cpk-1.67	Wires	3/90/0	3/90/0	3/90/0	3/90/0	3/90/0	1/30/0	6/180/0
PD	C4	JEDEC JESD22-B100 and B108	3	10	Physical Dimensions	Cpk-1.67	-	3/30/0	3/30/0	3/30/0	3/30/0	3/30/0	1/10/0	6/60/0
Test Group D - Die Fabrication Reliability Tests														
EM	D1	JESD61	-	-	Electromigration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
TDDb	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
HCI	D3	JESD60 & 28	-	-	Hot Carrier Injection	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
BTI	D4	-	-	-	Bias Temperature Instability	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
Test Group E - Electrical Verification Tests														
ESD	E2	AEC Q100-002	1	3	ESD HBM	-	2000 Volts	QBS MOG3507QPMRQ1	1/3/0	1/3/0	1/3/0	2/6/0	1/3/0	QBS MOL1306QRHBRQ1
ESD	E3	AEC Q100-011	1	3	ESD CDM	-	500 Volts	1/3/0	1/3/0	1/3/0	1/3/0	2/6/0	1/3/0	1/3/0
LU	E4	AEC Q100-004	1	6	Latch-Up	Per AEC Q100-004	-	QBS MOG3507QPMRQ1	1/3/0	1/3/0	1/3/0 ⁸	2/6/0	1/6/0	QBS MOL1306QRHBRQ1 ⁸
ED	E5	AEC Q100-009	3	30	Electrical Distributions	Cpk-1.67 Room, hot, and cold	-	3/90/0	1/30/0	3/90/0	3/90/0	6/180/0	3/90/0	3/90/0

1. TMS320F2837X*PTPQ supports MSL3 and was preconditioned to this MSL level for the Group A tests in this column. Additionally, for the Group A uHAST test, product TMS320F2837X*PTPQ was stressed at an equivalent condition, 130C, 85% RH for 96 hrs.
 2. CC2642R1TWRGZRQ1 supports MSL3 and was preconditioned to this MSL level for the Group A tests in this column. Additionally, for the Group A TC test, product CC2642R1TWRGZRQ1 was stressed at an equivalent condition, -55C/125C, for 1000 cycles.
 3. One unit also showed electrical overstress, which reflects handling and testing in a laboratory environment. This unit was discounted from the qualification population, but is reported, consistent with AEC-Q100.
 4. This test completed at both MSL1 and MSL2 conditions, including SAM review post 1000 cycles. All units passed, confirming support for MSL1, standard for SOT packages.
 5. While CC2642R1TWRGZRQ1 was stressed in the HTOL test at 125C for 1000 hrs in LFAB, this was ran at 105C for 1000 hrs in UMCI.
 6. For CC2642R1TWRGZRQ1, this ELFR was ran at Grade 2 conditions, including at 105C for both 24 hrs and 48 hrs; and 125C for 24 hrs. These tests included here as a reference.
 7. For CC2642R1TWRGZRQ1, the EDR test was conducted at only the high temperature condition.
 8. See Errata MSPM0L110x, MSPM0L13xx Microcontrollers (literature # SLAZ741), which outlines best practices to avoid excessive current injection.
- Qualification Devices MOL* in (SOT) DYY apackages are qualified at MSL1 260C.
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- Test B1, HTOL Life Test and test B3, the Data Retention Test, were preceded by endurance cycling
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles
- Ambient Operating Temperature by Automotive Grade Level:
- Grade 0 (or E): -40C to +150C
- Grade 1 (or Q): -40C to +125C
- Grade 2 (or T): -40C to +105C

Grade 3 (or I) : -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL, ED

Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room : AC/uHAST

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TI Qualification ID: R-CHG-2403-094, R-CHG-2409-031, R-CHG-2409-029, R-NPD-2306-083, R-NPD-2304-106, R-BKF-2205-007, R-CHG-2112-003, R-CHG-2206-036, R-NPD-2304-107

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